# MPI T5150-AIT | 150 mm Manual Probe System

# Industry's first explicitly designed 150 mm probe system providing accurate tests for mm-wave, THz, and automated impedance tuner applications

# **FEATURES / BENEFITS**

#### **Variety of Applications**

- Seamless integration of any banded, differential or broadband frequency extenders and automated impedance tuners
- Novel design of extenders/tuners integration for maximum of measurement dynamic
- Maximum on mechanical stability and repeatability combined with convenient and safety operation

#### **Ergonomic Design**

- Unique puck controlled air bearing stage for quick single-handed operation
- Rigid and large platen accommodates large area MicroPositioners, holding mmw extenders
- Highly repeatable platen lift design with three discrete positions for contact, separation, and loading

#### Upgradability

- Optional vibration isolated support for large automated impedance tuners
- Dedicated optics for shorting the cables and waveguide's lengths, for maximum of measurement directivity
- Various chuck options, PCB holders and a wide range of accessories such as DC/RF/mmW MicroPositioners



#### **SPECIFICATIONS**

#### **Chuck XY Stage (Standard)**

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Total travel range	180 x 300 mm (7.1 x 11.8 in)
Fine-travel range	25 x 25 mm fine micrometer control
Fine-travel resolution	< 1.0 μm (0.04 mils) @ 500 μm/rev
Planarity	< 10 µm
Theta travel (standard)	360°
Theta travel (fine)	± 5.0°
Theta resolution	7.5 x 10 <sup>-3</sup> gradient
Movement	Puck controlled air bearing stage

# **Chuck Z Stage**

Travel range	10 mm (0.4 in)
Fine-travel resolution	< 1.0 $\mu m$ (0.04 mils) @ 500 $\mu m/rev$ , with digital indicator

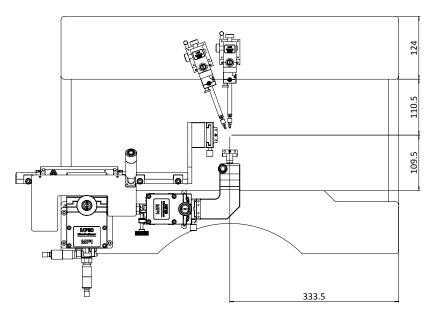
#### **Manual Microscope Stage (Linear)**

Movement range	50 x 50 mm (2 x 2 in) or 80 x 80 mm (3.15 x 3.15 in)
Resolution	< 5µm (0.2 mils)
Scope lift	Manual, tilt-back or vertical (depending on microscope type)
Movement	Independently controlled X and Y movement with locking screws

#### PROBE PLATEN

# **Specifications**

Design	For unsurpassed stability: low profile, four pole support
Material	Nickel plated steel
Dimension	Large area platen, see drawing
Chuck top to platen top	Min. 28 mm
Max. No of MicroPositioners	2x mmW E/W + 2x RF N/S and 4x DC or 2x mmW E/W + 8x DC
Platen lift control	3 positions - contact (0), separation (300 $\mu m),$ and loading (3 $mm)$
Separation repeatability	< 1 μm (0.04 mils) by "automated" control
mmW MicroPositioner mounting	Bolt down
RF MicroPositioner mounting	Magnetic with guided rail
DC MicroPositioner mounting	Magnetic



Probe Platen design for DC, RF and THz MicroPositioners

# Platen Lift with Probe Hover Control™

MPI Probe Hover Control  $^{\text{TM}}$  comes with hover heights (50, 100 or 150  $\mu m$ ) for easy and convenient probe to pad alignment.







# FREQUENCY EXTENDER ADAPTATION

Seamless integration of any frequency extenders for best measurement directivity at 200 mm wafers.







#### NON-THERMAL CHUCKS

#### **RF Wafer Chuck**

Connectivity	Coax BNC (f)	
Diameter	160 mm with 2 integrated AUX areas	
Material	Nickel Plated Aluminium (flat with 0.5 mm holes)	
Chuck surface	Planar with 0.5 mm diameter holes in centric sections	
Vacuum holes sections (diameter)	3, 27, 45, 69, 93, 117, 141 mm	
Vacuum actuation	Manual switch between Center (4 holes), 50, 100, 150 mm (2, 4, 6 in)	
Supported DUT sizes	Single DUTs down to 4 x 4 mm size or wafers 50 mm (2 in) thru 150 mm (6 in)*	
Surface planarity	≤± 5 μm	
Rigidity	< 15 μm / 10 N @edge	
<b>Electrical Specification</b>		
Operation voltage	In accordance with EC 61010, certificates for higher voltages available upon request	
Isolation	> 2 GΩ	

 $<sup>\</sup>hbox{$^*$Single DUT testing requires higher vacuum conditions dependent upon testing application.}}$ 

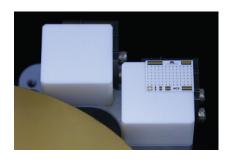
# mmW Wafer Chuck

Connectivity	N/A
Diameter	160 mm with 2 integrated AUX areas
Material	Ceramic with high tempearuture conductivity, RF absorbing material for accurate measurements at mm-wave and sub-mm wave (THz) frequency range
Chuck surface	Planar with 0.5 mm diameter holes in centric sections
Vacuum holes sections (diameter)	3, 27, 45, 69, 93, 117, 141 mm
Vacuum actuation	Manual switch between Center (4 holes), 50, 100, 150 mm (2, 4, 6 in)
Supported DUT sizes	Single DUTs down to 4 x 4 mm size or wafers 50 mm (2 in) thru 150 mm (6 in)*
Surface planarity	≤± 5 μm
Rigidity	< 15 μm / 10 N @edge

<sup>\*</sup>Single DUT testing requires higher vacuum conditions dependent upon testing application.

# **Auxiliary Chuck**

Quantity	2 AUX chucks
Position	Integrated to rear side of main chuck
Substrate size (W x L)	Max. 25 x 25 mm (1 x 1 in)
Material	Ceramic, RF absorbing material for accurate calibration
Surface planarity	≤± 5 μm
Vacuum control	Controlled independently, separate from chucks



MPI auxiliary chucks made by ceramic

# CONTACT / OVER-TRAVEL CONTROL

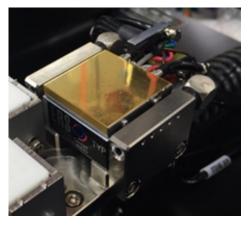


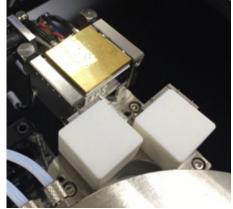
MPI offers the worldwide unique and most accurate contact / over-travel control with 1  $\mu m$  accuracy for easy measurement reproducibility and accuracy.

#### **THERMAL CHUCKS**

# **Specifications of MPI ERS Integrated Technology**

	35 °C to 150 °C	20 °C to 200 °C	25 °C to 150 °C	
Maximal wafer size	200 mm	200 mm	25 x 25 mm Single IC	
Connectivity	Coax BNC (f)	Coax BNC (f)	Coax BNC (f)	
Temperature control method	Cooling air / Resistance heater	Cooling air / Resistance heater	Peltier heater	
Coolant	Air (user supplied)	Air (user supplied)	Air (max. 50 l/min)	
Smallest temperature selection step	0.1 °C	0.1 °C	0.1 °C	
Chuck temperature display resolution	0.1 °C	0.01 °C	0.1 °C	
External touchscreen display operation	N/A	Yes	N/A	
Temperature stability	±0.5 °C	±0.08 °C	±0.2 °C	
Temperature accuracy	±1 °C	0.1 °C	±1 °C	
Control method	DC/PID	Low noise DC/PID	DC/PID	
Interfaces	RS232C	RS232C	RS232C	
Chuck surface plating	Nickel plated with pinhole surface	Nickel plated with pinhole surface	Gold plated with pinhole surface	
Temperature sensor	Pt100 1/3DIN	Pt100 1/3DIN, 4-line wired	Pt100 1/3DIN, 4-line wired	
Temperature uniformity	<±1 °C	<±0.5 °C	< ±0.5 °C	
Surface flatness and base parallelism	<±15 μm	<±10 μm	<±15 μm	
Heating and cooling rates	35 to 150 °C < 10 min 150 to 35 °C < 15 min	20 to 200°C < 15 mins 200 to 20°C < 15 mins	25 to 150 °C < 6 min 150 to 25 °C < 6 min	
Electrical isolation Coax BNC (f)	> 0.5 T Ω at 25 °C	> 10 T $\Omega$ at 25 °C > 300 G $\Omega$ at 200 °C	> 0.5 T Ω at 25 °C	
Leakage @ 10 V Kelvin Triax (f)	N/A	N/A	N/A	
Capacitance	< 750 pF	< 900 pF	< 750 pF	
Maximum voltage between chuck top and GND	500 V DC	500 V DC	500 V DC	





 $\label{lem:continuous} \textbf{Dedicated ERS thermal chuck system for testing single ICs}$ 

# FACILITY REQUIREMENTS

#### **Thermal Chuck Electrical Supply**

Electrical Supply	Hot only thermal chucks
Electrical primary connection	100 to 240 VAC auto switch
Frequency	50 Hz / 60 Hz
Compressed Air Supply	
Operating pressure	6.0 bar (0.6 MPa, 87 psi) at specified flow rate
CDA dew point	≤ 0 °C

#### **Controller Dimensions / Power and Air Consumption**

System Type	WxDxH(mm)	Weight (kg)	Power Cons. (VA)	max. Air Flow (l/min)
35 to 150 °C	300 x 265 x 135	10	500	200
20 to 200 °C	300 x 360 x 135	12	700	200
25 to 150 °C	300 x 261 x 135	3.3	100	50

# **General Probe System**

Power	100-240 V AC 50/60 Hz for optical accessories* only
Vacuum	-0.5 bar (for single DUT) / -0.3 bar (for wafers)
Compressed air	6.0 bar

<sup>\*</sup>e.g. microscope illumination, CCD cameras, monitors.

#### WARRANTY

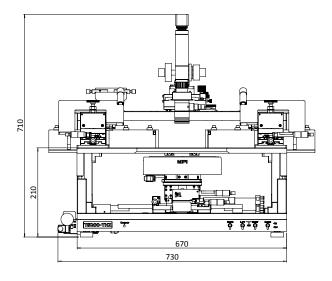
- Warranty\*: 12 months
- Extended service contract: contact MPI Corporation for more information

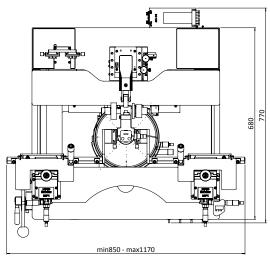
#### PHYSICAL DIMENSIONS

# Station Platform with Bridge\*

Dimensions (W x D x H)	670 x 680 x 710 mm (26.4 x 26.8 x 28.0 in)
Weight	~120 kg (265 lb.)

 $<sup>{}^{\</sup>star} Station\ accessories,\ such\ as\ different\ microscopes,\ cameras,\ or\ laser\ cutters,\ may\ change\ the\ total\ height.$ 

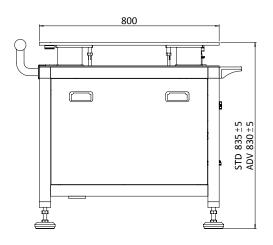


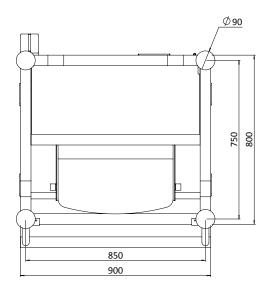


<sup>\*</sup>See MPI Corporation's Terms and Conditions of Sale for more details.

#### **Vibration Isolation Table**

	Standard	Advanced
Dimensions (W x D x H)	900 x 800 x 835 mm (35.4 x 31.5 x 32.9 in)	900 x 800 x 830 mm (35.4 x 31.5 x 32.7 in)
Feature	Adjustable air damping system	Automatic load leveling
Keyboard / Mouse Tray Included	Yes	
Front Protection Bar	Yes	
Castors Included	Yes	
Shelves Included	Upper and Lower	
Accessories Accepted	Monitor Stand(s) and Instrument Shelf	
Weight	Approx. 210 kg ( 463 lb.)	Approx. 210 kg ( 463 lb.)





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